



## 1. SCOPE

1.1 Scope. This drawing describes device requirements for class B microcircuits in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices".

1.2 Part or Identifying Number (PIN). The complete PIN shall be as shown in the following example:

<u>5962-88709</u>	<u>01</u>	<u>C</u>	<u>X</u>
Drawing number	Device type (1.2.1)	Case outline (1.2.2)	Lead finish per MIL-M-38510

1.2.1 Device type. The device type shall identify the circuit function as follows:

<u>Device type</u>	<u>Generic number</u>	<u>Circuit function</u>
01	54F36	Quadruple 2-input NOR gates

1.2.2 Case outlines. The case outlines shall be as designated in appendix C of MIL-M-38510, and as follows:

<u>Outline letter</u>	<u>Case outline</u>
C	D-1 (14-lead, .785" x .310" x .200"), dual-in-line package
D	F-2 (14-lead, .390" x .260" x .085"), flat package
2	C-2 (20-terminal, .358" x .358" x .100"), square chip carrier package

## 1.3 Absolute maximum ratings.

Supply voltage range	-0.5 V dc minimum to +7.0 V dc maximum
Input voltage range	-1.2 V at -18 mA to +7.0 V
Input current range	-30 mA to 5.0 mA
Voltage applied to any output in the high state	-0.5 V to 5.5 V
Current into any output in the low state	40 mA
Storage temperature range	-65° C to +150° C
Maximum power dissipation ( $P_D$ ) <sup>1/</sup>	71.5 mW
Lead temperature (soldering, 10 seconds)	+300° C
Thermal resistance, junction-to-case ( $\Theta_{JC}$ )	See MIL-M-38510, appendix C
Junction temperature( $T_J$ )	+175° C

## 1.4 Recommended operating conditions.

Supply voltage range ( $V_{CC}$ )	+4.5 V minimum to +5.5 V maximum
Minimum high level input voltage ( $V_{IH}$ )	2.0 V
Maximum low level input voltage ( $V_{IL}$ )	0.8 V
Input clamp current ( $I_{IC}$ )	-18 mA
High level output current ( $I_{OH}$ )	-1.0 mA
Low level output current ( $I_{OL}$ )	20 mA
Case operating temperature range ( $T_C$ )	-55° C to +125° C

<sup>1/</sup> Maximum power dissipation is defined as  $V_{CC} \times I_{CC}$ , and must withstand the added  $P_D$  due to short circuit test, e.g.  $I_{OS}$ .

**STANDARDIZED  
MILITARY DRAWING**  
DEFENSE ELECTRONICS SUPPLY CENTER  
DAYTON, OHIO 45444

SIZE  
**A**

**5962-88709**

REVISION LEVEL

SHEET  
**2**

## 2. APPLICABLE DOCUMENTS

2.1 Government specification, standard, and bulletin. Unless otherwise specified, the following specification, standard, and bulletin of the issue listed in that issue of the Department of Defense Index of Specifications and Standards specified in the solicitation, form a part of this drawing to the extent specified herein.

### SPECIFICATION

#### MILITARY

MIL-M-38510 - Microcircuits, General Specification for.

### STANDARD

#### MILITARY

MIL-STD-883 - Test Methods and Procedures for Microelectronics.

(Copies of the specification and standard required by manufacturers in connection with specific acquisition functions should be obtained from the contracting activity or as directed by the contracting activity.)

2.2 Order of precedence. In the event of a conflict between the text of this drawing and the references cited herein, the text of this drawing shall take precedence.

## 3. REQUIREMENTS

3.1 Item requirements. The individual item requirements shall be in accordance with 1.2.1 of MIL-STD-883, "Provisions for the use of MIL-STD-883 in conjunction with compliant non-JAN devices" and as specified herein.

3.2 Design, construction, and physical dimensions. The design, construction, and physical dimensions shall be as specified in MIL-M-38510 and herein.

3.2.1 Terminal connections. The terminal connections shall be as specified on figure 1.

3.2.2 Truth table. The truth table shall be as specified on figure 2.

3.2.3 Test circuit and switching waveform. The test circuit and switching waveform shall be as specified on figure 3.

3.2.4 Case outlines. The case outlines shall be in accordance with 1.2.2 herein.

3.3 Electrical performance characteristics. Unless otherwise specified herein, the electrical performance characteristics are as specified in table I and apply over the full case operating temperature range.

3.4 Marking. Marking shall be in accordance with MIL-STD-883 (see 3.1 herein). The part shall be marked with the part number listed in 1.2 herein. In addition, the manufacturer's part number may also be marked as listed in 6.4 herein.

3.5 Certificate of compliance. A certificate of compliance shall be required from a manufacturer in order to be listed as an approved source of supply in 6.4. The certificate of compliance submitted to DESC-ECS prior to listing as an approved source of supply shall state that the manufacturer's product meets the requirements of MIL-STD-883 (see 3.1 herein) and the requirements herein.

<b>STANDARDIZED MILITARY DRAWING</b> DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE <b>A</b>		<b>5962-88709</b>
		REVISION LEVEL	SHEET <b>3</b>

TABLE I. Electrical performance characteristics.

Test	Symbol	Conditions 1/ -55°C ≤ T <sub>C</sub> ≤ +125°C unless otherwise specified	Group A subgroups	Limits		Unit
				Min	Max	
High level output voltage	V <sub>OH</sub>	V <sub>CC</sub> = 4.5 V V <sub>IL</sub> = 0.8 V V <sub>IH</sub> = 2.0 V I <sub>OH</sub> = -1.0 mA 2/ 3/	1, 2, 3	2.5		V
Low level output voltage	V <sub>OL</sub>	V <sub>CC</sub> = 4.5 V V <sub>IL</sub> = 0.8 V V <sub>IH</sub> = 2.0 V I <sub>OL</sub> = 20 mA 2/ 4/	1, 2, 3		0.5	V
Input clamp voltage	V <sub>IC</sub>	V <sub>CC</sub> = 4.5 V I <sub>IN</sub> = -18 mA	1, 2, 3		-1.2	V
Low level input current	I <sub>IL</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 0.5 V Unused inputs = 4.5 V	1, 2, 3		-0.6	mA
High level input current	I <sub>IH1</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 2.7 V Unused inputs = 0.0 V	1, 2, 3		20	μA
	I <sub>IH2</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 7.0 V Unused inputs = 0.0 V	1, 2, 3		0.1	mA
Short circuit output current	I <sub>OS</sub>	V <sub>CC</sub> = 5.5 V V <sub>OUT</sub> = 0.0 V 5/	1, 2, 3	-60	-150	mA
Supply current	I <sub>CCH</sub>	V <sub>CC</sub> = 5.5 V V <sub>IN</sub> = 0.0 V (all inputs)	1, 2, 3		5.6	mA
	I <sub>CCL</sub>	V <sub>CC</sub> = 5.5 V One input per gate at 4.5 V and all others grounded.	1, 2, 3		13	mA
Functional tests		See 4.3.1c 6/	7, 8			
Propagation delay time, A or B to Y	t <sub>PLH</sub>	V <sub>CC</sub> = 4.5 V to 5.5 V C <sub>L</sub> = 50 pF R <sub>L</sub> = 500Ω See figure 3 7/	9, 10, 11	1.7	7.5	ns
	t <sub>PHL</sub>		9, 10, 11	1	6.5	ns

See footnotes on next page.

**STANDARDIZED  
MILITARY DRAWING**  
DEFENSE ELECTRONICS SUPPLY CENTER  
DAYTON, OHIO 45444

SIZE  
**A**

5962-88709

REVISION LEVEL

SHEET  
**4**

- 1/ Unused inputs that do not directly control the pin under test must be  $\geq 2.5$  V or  $\leq 0.5$  V, and shall not exceed 5.5 V or go less than 0.0 V. No inputs shall be floated.
- 2/ All outputs must be tested. In the case where only one input at  $V_{IL}$  maximum or  $V_{IH}$  minimum produces the proper output state, the test must be performed with each input being selected as the  $V_{IL}$  maximum or  $V_{IH}$  minimum input.
- 3/ One input to gate under test = 0.8 V, other inputs  $\leq 0.8$  V.
- 4/ One input to gate under test = 2.0 V, other inputs  $\leq 0.8$  V.
- 5/ Not more than one output shall be shorted at one time and the duration of the test condition shall not exceed one second.
- 6/ Functional tests shall be conducted at input test conditions of  $GND \leq V_{IL} \leq V_{OL}$  and  $V_{OH} \leq V_{IH} \leq V_{CC}$ .
- 7/ Propagation delay limits are based on single output switching. Unused inputs = 0.0 V or 3.0 V.

3.6 Certificate of conformance. A certificate of conformance as required in MIL-STD-883 (see 3.1 herein) shall be provided with each lot of microcircuits delivered to this drawing.

3.7 Notification of change. Notification of change to DESC-ECS shall be required in accordance with MIL-STD-883 (see 3.1 herein).

3.8 Verification and review. DESC, DESC's agent, and the acquiring activity retain the option to review the manufacturer's facility and applicable required documentation. Offshore documentation shall be made available onshore at the option of the reviewer.

#### 4. QUALITY ASSURANCE PROVISIONS

4.1 Sampling and inspection. Sampling and inspection procedures shall be in accordance with section 4 of MIL-M-38510 to the extent specified in MIL-STD-883 (see 3.1 herein).

4.2 Screening. Screening shall be in accordance with method 5004 of MIL-STD-883, and shall be conducted on all devices prior to quality conformance inspection. The following additional criteria shall apply:

a. Burn-in test, method 1015 of MIL-STD-883.

(1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).

(2)  $T_A = +125^\circ\text{C}$ , minimum.

b. Interim and final electrical test parameters shall be as specified in table II herein, except interim electrical parameter tests prior to burn-in are optional at the discretion of the manufacturer.

4.3 Quality conformance inspection. Quality conformance inspection shall be in accordance with method 5005 of MIL-STD-883 including groups A, B, C, and D inspections. The following additional criteria shall apply.

##### 4.3.1 Group A inspection.

a. Tests shall be as specified in table II herein.

b. Subgroups 4, 5, and 6 in table I, method 5005 of MIL-STD-883 shall be omitted.

c. Subgroups 7 and 8 tests shall verify the truth table as specified on figure 2 herein.

<b>STANDARDIZED MILITARY DRAWING</b> DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE <b>A</b>		<b>5962-88709</b>
		REVISION LEVEL	SHEET <b>5</b>

Case outlines	C and D	2
Terminal number	Terminal symbol	
1	1A	NC
2	1B	1A
3	1Y	1B
4	2A	1Y
5	2B	NC
6	2Y	2A
7	GND	NC
8	3Y	2B
9	3A	2Y
10	3B	GND
11	4Y	NC
12	4A	3Y
13	4B	3A
14	V <sub>CC</sub>	3B
15	---	NC
16	---	4Y
17	---	NC
18	---	4A
19	---	4B
20	---	V <sub>CC</sub>

NC = No connection

FIGURE 1. Terminal connections.

Inputs		Output
A	B	Y
H	X	L
X	H	L
L	L	H

H = High level voltage  
L = Low level voltage  
X = Irrelevant

FIGURE 2. Truth table.

<b>STANDARDIZED MILITARY DRAWING</b> DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE <b>A</b>		5962-88709
		REVISION LEVEL	SHEET <b>6</b>



TABLE II. Electrical test requirements.

MIL-STD-883 test requirements	Subgroups (per method 5005, table I)
Interim electrical parameters (method 5004)	---
Final electrical test parameters (method 5004)	1*, 2, 3, 7, 8, 9, 10, 11
Group A test requirements (method 5005)	1, 2, 3, 7, 8, 9, 10, 11
Groups C and D end-point electrical parameters (method 5005)	1, 2, 3

\* PDA applies to subgroup 1.

#### 4.3.2 Groups C and D inspections.

- a. End-point electrical parameters shall be as specified in table II herein.
- b. Steady-state life test, method 1005 of MIL-STD-883.
  - (1) Test condition A or D using the circuit submitted with the certificate of compliance (see 3.5 herein).
  - (2)  $T_A = +125^\circ\text{C}$ , minimum.
  - (3) Test duration: 1,000 hours, except as permitted by method 1005 of MIL-STD-883.

#### 5. PACKAGING

5.1 Packaging requirements. The requirements for packaging shall be in accordance with MIL-M-38510.

#### 6. NOTES

6.1 Intended use. Microcircuits conforming to this drawing are intended for use when military specifications do not exist and qualified military devices that will perform the required function are not available for OEM application. When a military specification exists and the product covered by this drawing has been qualified for listing on QPL-38510, the device specified herein will be inactivated and will not be used for new design. The QPL-38510 product shall be the preferred item for all applications.

6.2 Replaceability. Microcircuits covered by this drawing will replace the same generic device covered by a contractor-prepared specification or drawing.

6.3 Comments. Comments on this drawing should be directed to DESC-ECS, Dayton, Ohio 45444, or telephone 513-296-5375.

<b>STANDARDIZED MILITARY DRAWING</b> DEFENSE ELECTRONICS SUPPLY CENTER DAYTON, OHIO 45444	SIZE <b>A</b>		5962-88709
		REVISION LEVEL	SHEET <b>8</b>



6.4 Approved source of supply. An approved source of supply is listed herein. Additional sources will be added as they become available. The vendor listed herein has agreed to this drawing and a certificate of compliance (see 3.5 herein) has been submitted to DESC-ECS.

Military drawing part number	Vendor CAGE number	Vendor similar part number <u>1/</u>
5962-8870901CX	01295	SNJ54F36J
5962-8870901DX	01295	SNJ54F36W
5962-88709012X	01295	SNJ54F36FK

1/ Caution. Do not use this number for item acquisition.  
Items acquired to this number may not satisfy the  
performance requirements of this drawing.

Vendor CAGE  
number

01295

Vendor name  
and address

Texas Instruments, Incorporated  
P.O. Box 6448  
Midland, TX 79711

**STANDARDIZED  
MILITARY DRAWING**  
DEFENSE ELECTRONICS SUPPLY CENTER  
DAYTON, OHIO 45444

SIZE  
**A**

**5962-88709**

REVISION LEVEL

SHEET  
**9**